Sieve Shaking Machines

The AS200 Sieve shakers are designed to carry out exact, reproducible results according to DIN EN ISO 9000 ff. The AS200 is available with three different control systems, and options on clamping devices to suit the customer's requirements and budgets. The AS200 has a capacity of 8 full height or 16 half height sieves of 100/150/200/203mm (8").

AS200 Control The AS 200 control complies with the highest requirements in quality assurance. One particular characteristic makes this RETSCH product stand out from others: Instead of the vibration height, the sieve acceleration, which is independent of the power frequency, can be set. Thus, the AS 200 control ensures comparable and reproducible sieving results worldwide.

It can be calibrated to ensure 100% reproducibility of sieving results, not only in one device, but among all AS 200 control units! Thus, the requirement for the test materials monitoring according to DIN EN ISO 9000 ff is met. Its microprocessor-controlled measuring and control unit ensures a constant vibration height. With regard to operational convenience, the AS 200 control meets and exceeds all standards of a modern laboratory. All sieving parameters - vibration height, time, interval - are set, displayed and monitored digitally. Up to 9 parameter combinations can be stored for routine analyses

Through the integrated interface the instrument can be connected to a PC and controlled with the evaluation software EasySieve®. This program enables you to control the whole sieving process and the subsequent documentation with convenience and accuracy.



AS200 Digit, the standard model of the AS 200 series is recommended whenever digital time display, interval operation and analogue adjustment along with optical monitoring of the vibration height are required



AS200 Basic The economical alternative of the series with familiar quality and reliability. With analogue adjustment of vibration height and sieving time.



Technology of AS 200, AS 300

All sieve shakers of the series AS 200 and AS 300 work with an electromagnetic drive that is patented by RETSCH (EP 0642844).

This drive produces a 3D throwing motion that moves the product to be sieved equally over the whole sieving surface. The advantage: high load capacity, extremely smooth operation and short sieving times with high separation efficiency.

Product Codes (for 230V, 50Hz supply - other voltages on request)

AS200 Control (100-240V, 50/60Hz)	30.018.0001	Clamping device "deluxe"	32.662.0001	Universal Clamping deluxe	32.662.0004
AS200 Digit	30.015.0001	Clamping device "standard"	32.662.0002	Universal Clamping standard	32.662.0005
AS200 Basic	31.016.0001	Clamping device "economy"	32.662.0003	EasySieve software (English)	32.645.0026



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EasySieve® Standard or EasySieve® Comfort

Two different versions of EasySieve® are available: Standard and Comfort. EasySieve® Comfort offers enhanced possibilities for data transfer to LIMS systems, for graphical display of trend analyses as well as for the determination of special characteristics. Available in German and in English



Benefits at a glance

• Automatic registration, evaluation and administration of measurement data

- Measurement protocol in accordance with standards
- Complex transformation into charts and tables
- Data link of different measurement instruments

• Automatic detection and configuration of common analytical scales

• Comprehensive data export

Comprehensive help text, detailed manual

Simple, fast, and reliable

EasySieve, the software for particle size analyses, is able to automatically control the necessary measurement and weighing procedures – from the registration of the weight of the sieve up to the evaluation of the data.

Due to the logical design of the software the user can easily get started with the program. He is lead through the process step by step.

System requirements

Pentium PC

for automatic control:

- PC with free serial * interfaces
- scale with serial * interface
- sieve shaker with serial * interface

(e.g. AS 200 control, AS 300 control, AS 400 control, AS 200 tap)

*A RS232-USB Adapter is available

Feature	COMFORT	STANDARD
Windows user interface	Windows 98/98/ME/	Windows 98/98/ME/
	NT/2000/XP	NT/2000/XP
ASTM & Tyler Mesh	Х	-
Password Protection	Х	-
Serial No for Sieves	Х	-
Sieve analysis with:		
Nominal mesh size	Х	Х
Actual mesh size	Х	-
GENERAL INFORMATION		
Automatic simultaneous data transfer	Х	-
Administration of measure-	Unlimited	Unlimited
ment data	oninitiou	Criminitou
Data import & export	Х	Х
CD manual / omline help	X	X
Measurement protocol	X	X
(according to DIN 66 165)	~	~
TABLES		
Throughput value, Q3 (x)	Х	Х
Residual values, 1-Q3 (x)	X	X
Fraction, p3	X	X
Fraction, Δm (proportional	X	X
masses)	^	^
Distribution Density, q3 (x)	Х	Х
Log distribution density, q3*	X	X
(x)		
Actual mesh size	Х	-
DIAGRAM		
combined representation of	Х	
several analyses		
Curve representation	Х	Х
Distribution density		
Distribution density • x-axis	lin, log	lin, log
Distribution density • x-axis • Y-axis	lin, log, RSSB	lin, log, RSSB
Distribution density • x-axis • Y-axis Windowing (Zoom)	lin, log, RSSB X	lin, log, RSSB
Distribution density • x-axis • Y-axis Windowing (Zoom) Cumulative curve	lin, log, RSSB	lin, log, RSSB
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